

Search Notes

Application/Control No.

10/500,210

Examiner

W. Patty Chen

Applicant(s)/Patent under
Reexamination

YAMASHITA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
349/114 combined with key words search of all databases in EAST	9/20/2007	WPC
349/106 combined with key words search of all databases in EAST	9/20/2007	WPC